

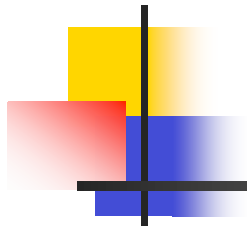
Development of Conduction, Convection, Spreading and Contact Resistance Models for Microelectronics Applications

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Outline

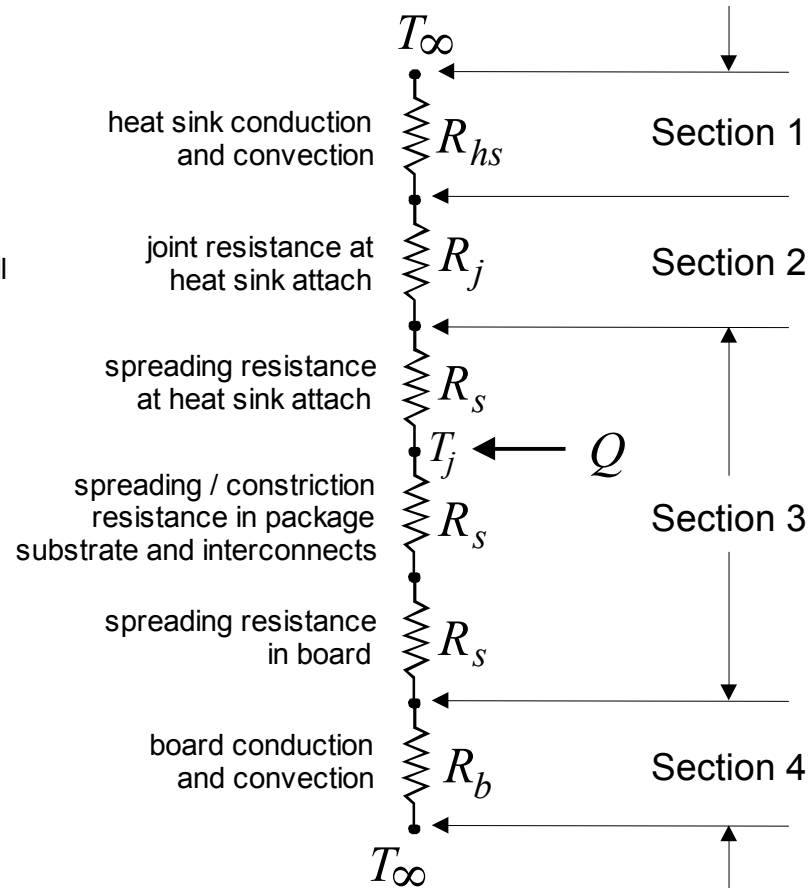
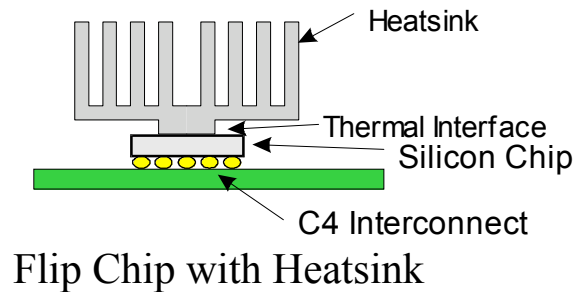
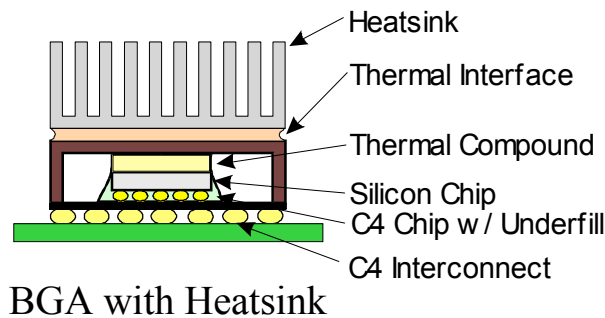


- Project Overview
- Objectives
- Year 1 Deliverables
- Design & Analysis Tools
- Personnel
- What Lies Ahead
- Concluding Comments

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Project Strategy



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Objectives

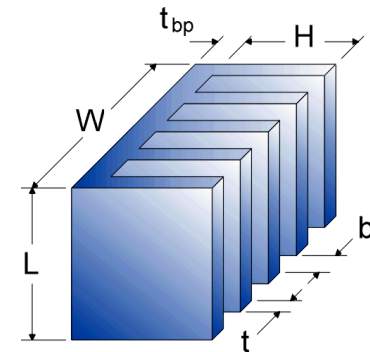


- Thermal model development:
chip level → cooling medium
 - ✓ heat sink optimization
 - ✓ modeling & characterization of thermal interfaces
 - ✓ modeling of spreading & constriction resistance
 - ✓ modeling of conduction & convection in PWBs

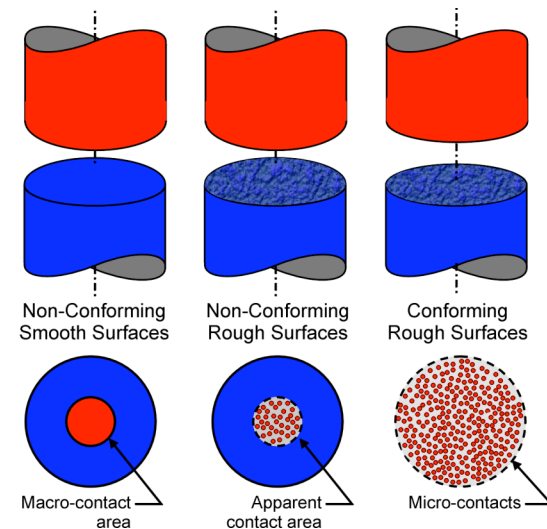
Year 1 Deliverables



- Heat sink optimization model
 - ✓ shrouded, air-cooled, plate fin heat sink
 - ✓ interactive web-based modeling tool



- Thermal resistance models
 - ✓ non-conforming, smooth surfaces
 - ✓ conforming rough surfaces
 - ✓ Excel spreadsheet models



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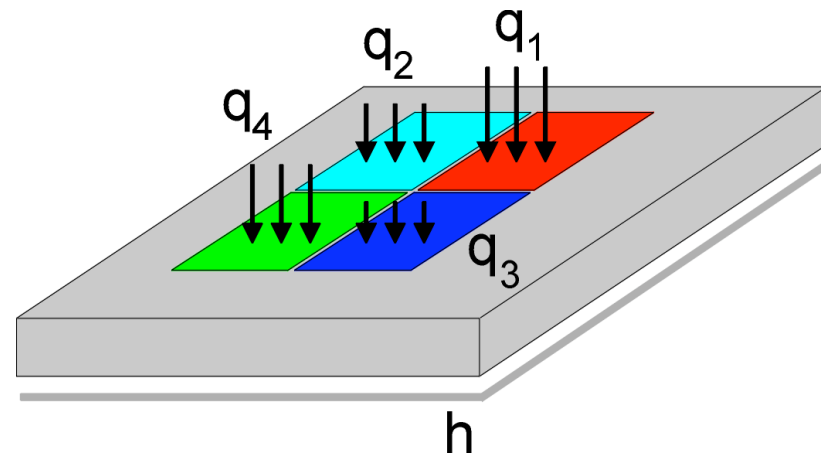
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Year 1 Deliverables



■ Spreading resistance model for

- ✓ multiple discrete sources
- ✓ isotropic or multi-layered substrate
- ✓ interactive web-based modeling tool



■ Thermal Interface Test Rig

- ✓ design, build and commission test apparatus

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Heat Sink Optimization



Analysis Tool

vs.

Design Tool

- design is known a priori
- used to calculate the performance of a given design,
i.e. Nu or R vs. Re
- cannot guarantee an optimized design

- used to obtain an optimized design for a set of known constraints i.e.

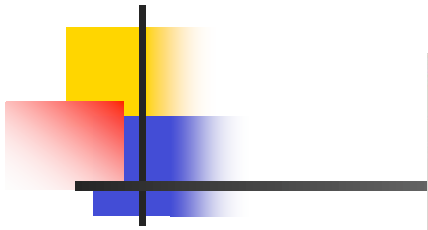
given:

- ✓ maximum temperature
- ✓ heat input
- ✓ maximum outside dimensions

find: the most efficient design

Why use Entropy Generation Minimization?

- entropy production \propto amount of energy degraded to a form unavailable for work
- lost work is an additional amount of heat that could have been extracted
- degradation process is a function of thermodynamic irreversibilities e.g. friction, heat transfer etc.
- minimizing the production of entropy, provides a simultaneous optimization of all design variables



Heat Sink Optimization: Plate Fin - Microsoft Internet Explorer

File Edit View Favorites Tools Help

Back Forward Stop Search Favorites Media

Heat Sink Optimization: Plate Fin

[Instructions](#) [Background](#) [Input/Output](#) [References](#)

Optimize Value

Base Plate

Length 100 mm

Width 100 mm

Thickness 10 mm

Fin

Height 50 mm

Thickness 2 mm

Number

Thermal Conductivity

Fin 180 W/mK

Baseplate 180 W/mK

Approach Velocity 2 m/s

Maximum Dimensions

L	W	H
100 mm	100 mm	50 mm

Calculate Reset

Typical Run times

Variables	1	2	3	4
Time (min)	1	3	10	30

Value: provide specific values for constrained parameters

Optimize: indicate parameters to be optimized

Calculate: run optimization code to calculate design parameters for maximum thermal-fluid performance

Web URL: <http://mhtlab.uwaterloo.ca/onlinetools/optimize/index.html>

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Contact Resistance Models



- **Non-conforming, smooth surfaces:**
 - ✓ assume material waviness (out-of-flatness) predominates
 - ✓ microscopic roughness is negligible
 - ✓ example: heat sink on a silicon chip
 - ✓ determine contact, gap and joint resistance

- **Conforming rough surfaces:**
 - ✓ assume microscopic roughness predominates
 - ✓ out-of-flatness is negligible
 - ✓ example: two machined (lapped or ground) surfaces
 - ✓ determine contact, gap and joint resistance

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Non-Conforming Smooth Surfaces



Contact Resistance for Non-Conforming Smooth Surfaces

$q = Q / A$

$R = \frac{\bar{T}_s - T_f}{Q} \quad h = \frac{Q_{\text{heat sink}}}{A_{\text{interface}} \Delta T_{\text{heat sink}}}$

Chip and Heat Sink Geometry		
	Chip	Heat Sink
Width (mm)	15	6
Length (mm)	15	6
Out of flatness (mm)	0.00762	0.00762
Thickness (mm)	0.75	0.5

Chip and Heat Sink Material		
	Chip	Heat Sink
Material	Silicon	Al 6063T5
k (W/m.K)	125	209
E (GPa)	163	70
Poisson ratio	0.30	0.30

Gap	
Material	Air
P(atm)	1
T (°C)	50
k(W/m.K)	0.028
Beta [-]	1.643
Alpha [-]	2.44
Lambda (Micro m)	0.064

Results	
	Resistance (K/W)
Chip	
Heat Sink	
Gap	
Total	
Decimals	3

Condition	
h (W/(m ² .K))	500
Contact Load (N)	7.41

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Conforming Rough Surfaces



Contact Resistance for Conforming Rough Surfaces

Surfaces Geometry		
	Width (mm)	Length (mm)
Surface 1	15	15
Surface 2	6	6

Surface Information			
Material	Conductivity (W/m.K)	Roughness ($m \times 10^{-6}$)	Microhardness (MPa)
Al 6063 (Flycut)	201	0.4	1094
Alumina (96% Al ₂ O ₃)(Ground)	20.9	1.3	3100

Contact Pressure

Contact Pressure (MPa)

Gap Information

Material	Temp. (°C)	Pressure (atm.)	Conductivity (W/m.K)	Gap Parameter $M0 \times 10^6$, (m)
Air	50	1	0.028	0.373

Thermal Resistance (K/W)

Contact Resistance Decimal

Gap Resistance

Joint Resistance

Calculate

Exit

Help

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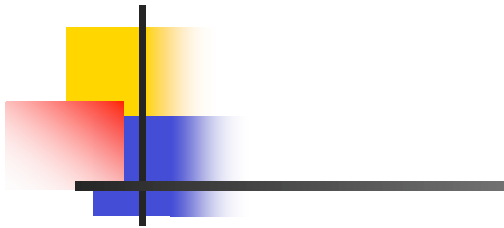
Spreading Resistance Model



- Analytical solution for heat sources on a rectangular flux channel
 - ✓ isotropic or laminated substrates
 - ✓ multiple discrete sources

- Model details in:

“Muzychka, Y.S., Culham, J.R. and Yovanovich, M.M., 2000, *Thermal Spreading Resistance of Eccentric Heat Sources on Rectangular Flux Channels*,” ASME IMECE, Orlando, FL, November 5-10.



- Instructions:** user's guide & sample problem
- Background:** governing eqns. & model development
- Input/Output:** data entry & units
- References:** publications & sample pdf files

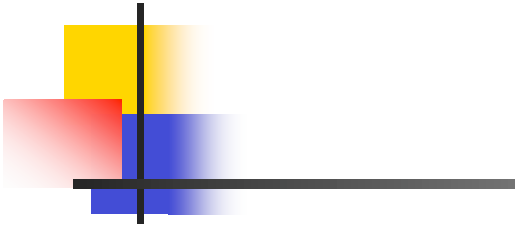
- Properties:** set substrate & source properties
- Add/move, Edit, Delete, New, Copy:** on screen package placement

Note: Java source requires Netscape (IE will not work)

Web URL: <http://mhtlab.uwaterloo.ca/onlinetools/multisource/index.html>

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Multisource - Netscape

File Edit View Go Communicator Help

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Bookmarks Location: [ca/onlinetools/multisource/multisource.htm](http://ca.onlinetools/multisource/multisource.htm) What's Related

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Spreading Resistance of Multiple Sources on Rectangular Substrate

[Instructions](#) [Background](#) [Input/Output](#) [References](#)

Package located at 23.5, 39.125

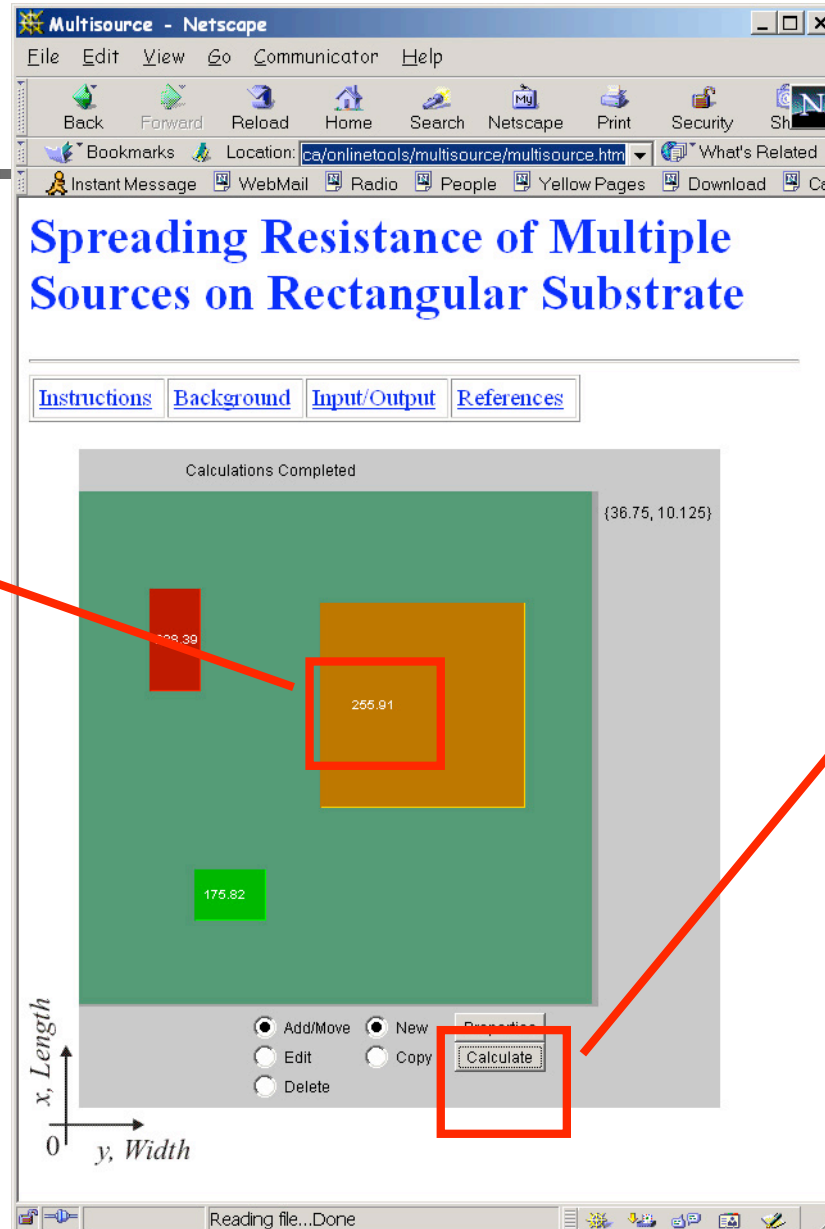
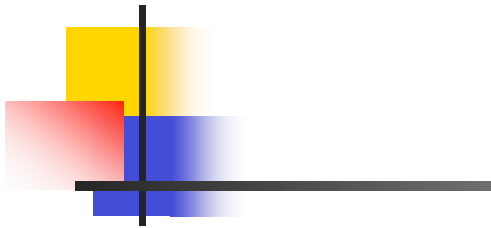
(41.625, 9.5)

Add/Move New Properties
 Edit Copy Calculate
 Delete

Add a new source: a pop-up window will appear for entering heat source inputs
- click on substrate to place current heat source

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Mean source temperature rise - $^{\circ}\text{C}$

Calculate: click calculate to obtain mean heat source temperature rise for each source

- Java-based code will be executed on local CPU
- typical run times are approximately 10 seconds per source

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Thermal Interface Materials



- Design, build & commission test apparatus & data acquisition interface for testing interface materials:
 - ✓ Measure joint resistance and thermal conductivity as function of:
 - interface temperature
 - contact pressure
 - material properties
 - surface characteristics
 - ✓ in-situ thickness measurement: sub micron precision

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Testing Capabilities

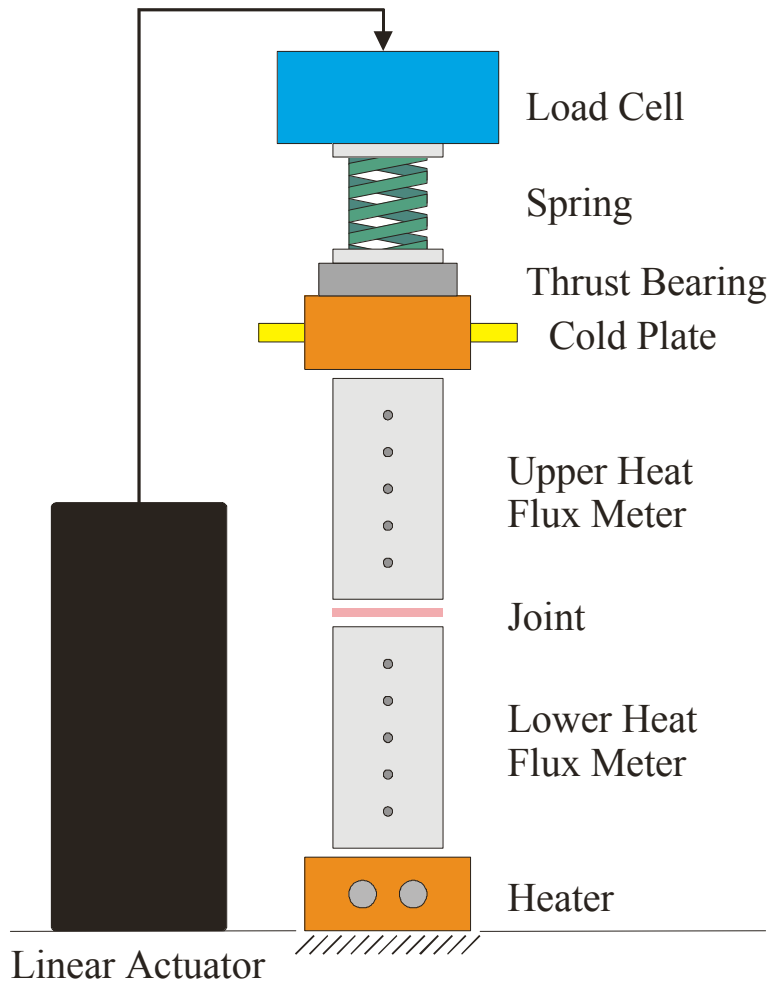


- 4 categories of materials can be tested
 - ✓ materials requiring stops & minimal clamping force
 - grease, liquids, phase change
 - ✓ materials deforming more than 10% under clamping force - compliant materials
 - ✓ materials deforming less than 10%, no stops required - hard rubber
 - ✓ thermally conductive materials requiring high clamping force - ceramics & plastics

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Apparatus

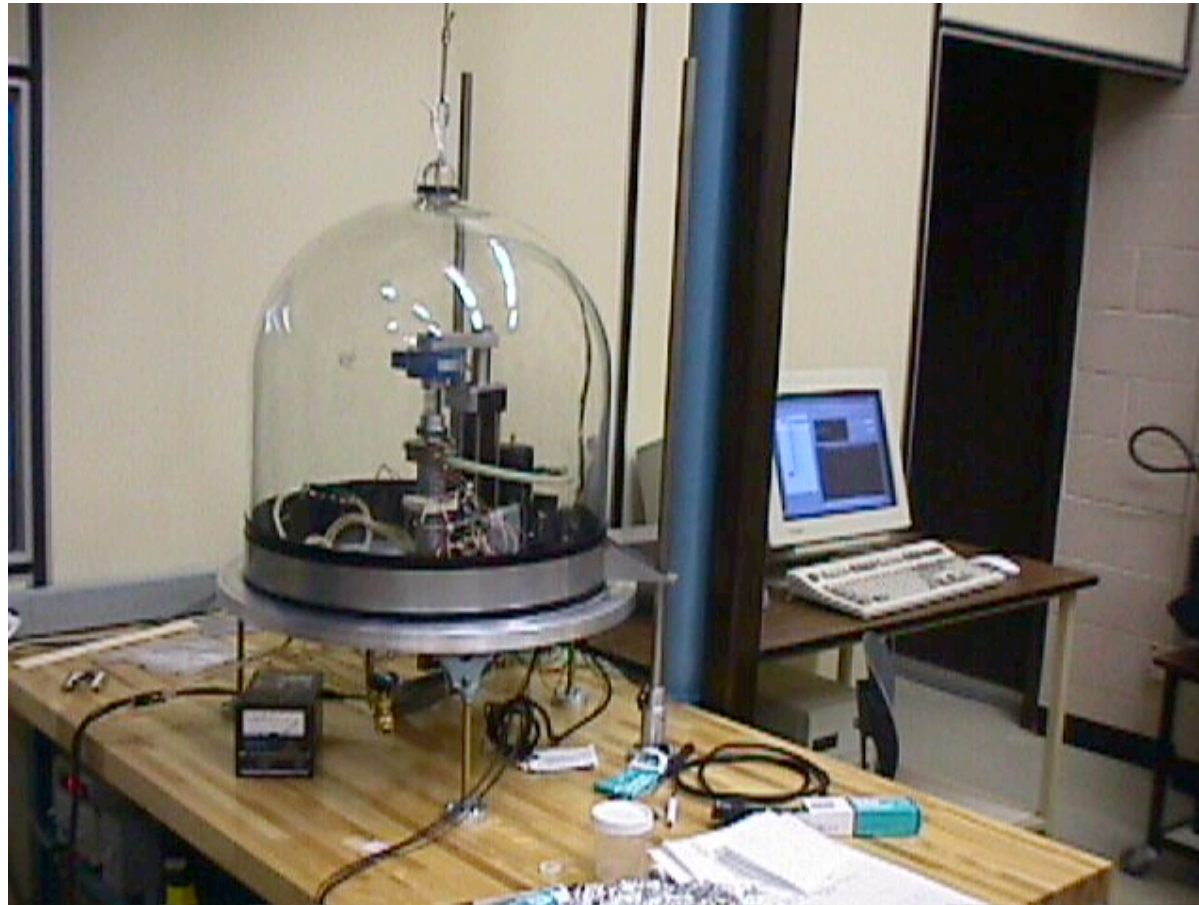


- Load cell
 - ✓ 100 or 1000 lbs
- Spring to compensate for thermal expansion
- Thrust bearing to remove torque loads
- Electric cylinder
 - ✓ digitally controlled stepper motor
 - ✓ 400 steps / rev 0.1" per revolution

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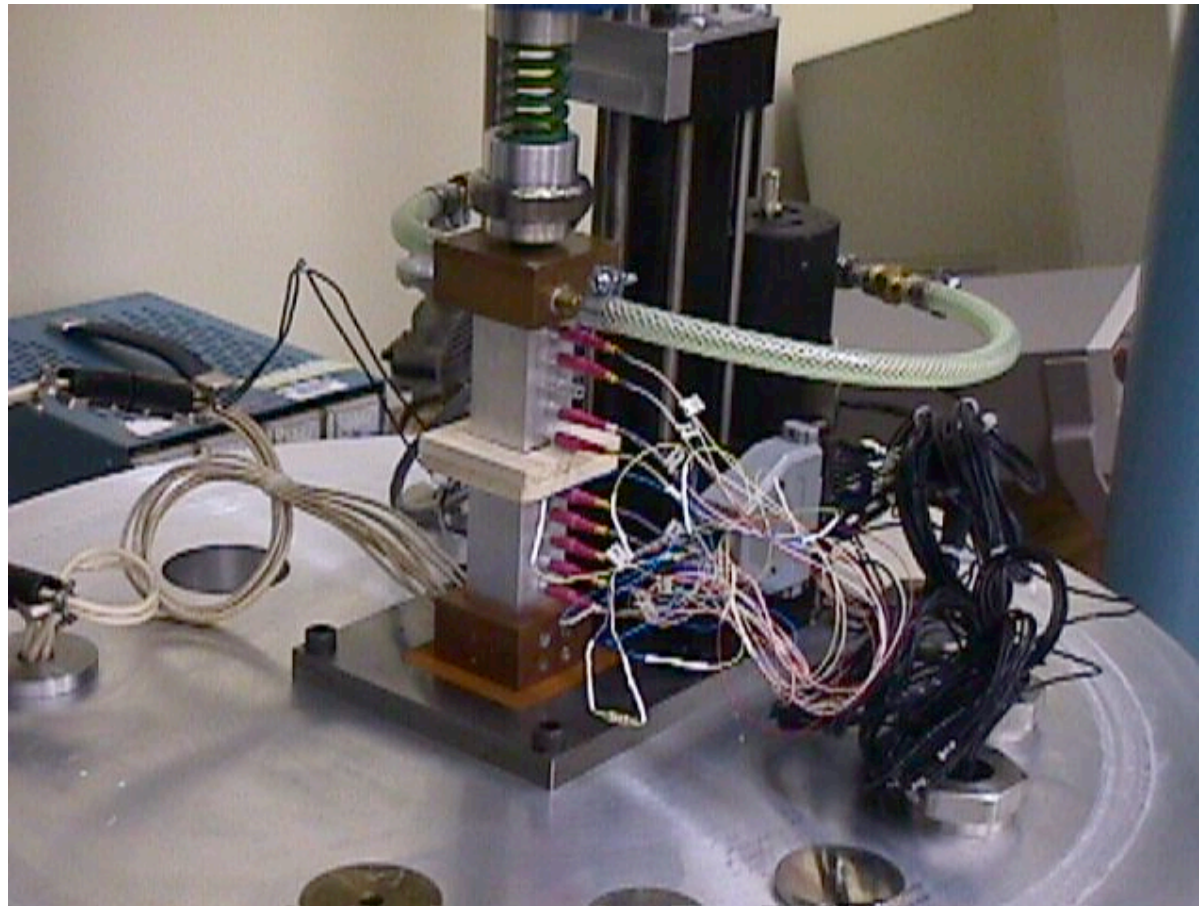
Thermal Interface Test Apparatus



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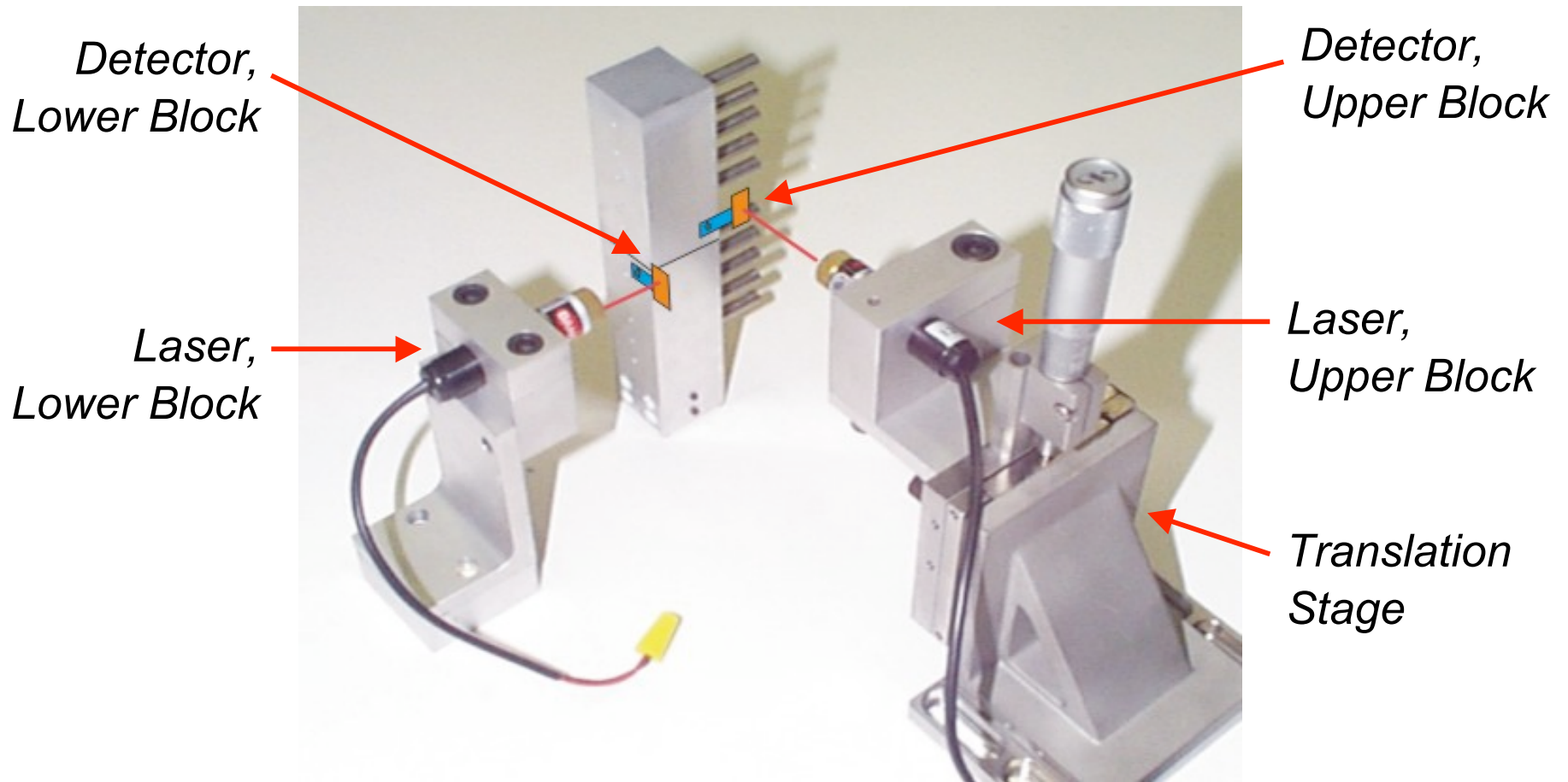
Thermal Interface Test Apparatus



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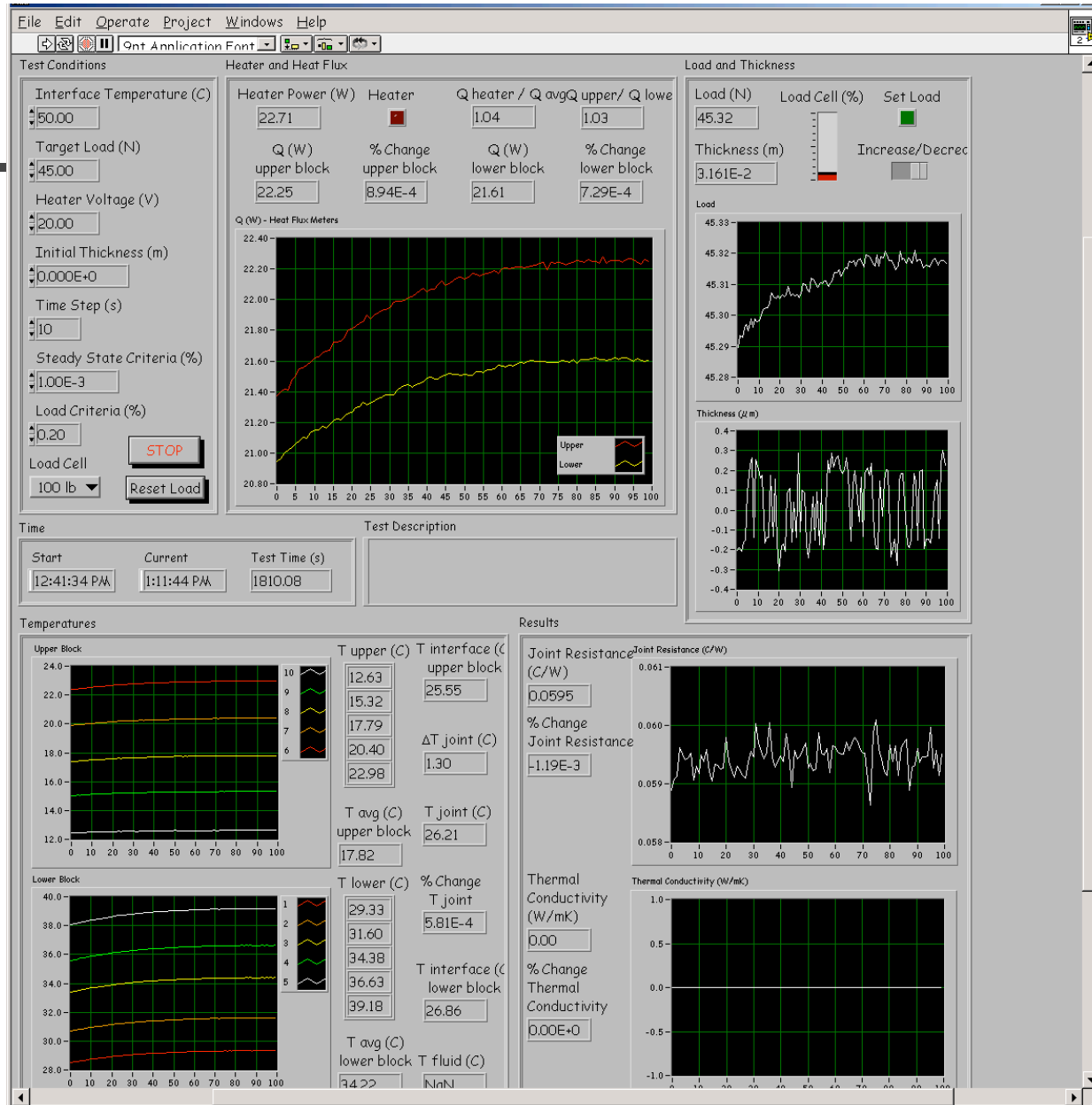
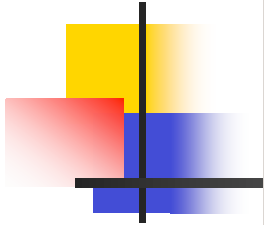
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Thickness and Deflection



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HQP's



- Graduate Students
 - ✓ Mr. Majid Bahrami
 - Ph.D candidate - *topic*: contact resistance in non-conforming rough surfaces
 - ✓ Ms. Irena Savija
 - M.A.Sc. Candidate - *topic*: modeling and characterization of thermal interface materials
- Summer Students
 - ✓ Mr. Joel Reardon and Mr. Chris Hurley
 - Web tool model development: Java, C, Javascript, CGI
- Senior Undergraduate Projects
 - ✓ Dana Frigula and Matthew Morrissey
 - Laser measurement system

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What Lies Ahead



- Heat sink models for base plate enhancements such as copper inserts, laminates and heat pipes
- Heat sink flow by-pass models
- Joint resistance models for non-conforming rough surfaces
- Thermal interface models: grease, phase change materials and compliant polymers
- Board level modeling

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Concluding Comments



- Thank you to sponsoring companies:
 - ✓ Alcatel
 - ✓ Celestica
 - ✓ Dy4
 - ✓ Coretec
- Cross our fingers for a successful CFI bid in the new year

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